## Notice of References Cited Application/Control No. 10/606,998 Applicant(s)/Patent Under Reexamination CHOWDHURY, KUNTAL Examiner /BINH K. TIEU/ Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0167905	11-2002	Wenzel et al.	370/249
*	В	US-2004/0008649	01-2004	Wybenga et al.	370/338
	U	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
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	Ρ					
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	S					
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## **NON-PATENT DOCUMENTS**

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